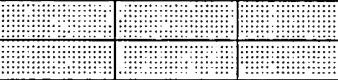


Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/660,078	RHEE, SHIN W.
Examiner	Art Unit	
Jacob Y. Choi	2875	

ISSUE CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)						
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
362	267	362	223	260	329			
INTERNATIONAL CLASSIFICATION								
F	2	1	V	29/00	/	/	/	/
Jacob Y. Choi 06/01/2005 (Assistant Examiner) (Date)							Total Claims Allowed: 8	
C.P.: 6/13/05 (Legal Instruments Examiner) (Date)				JOHN ANTHONY WARD PRIMARY EXAMINER (Primary Examiner) 6/10/05 			O.G. Print Claim(s) 6	O.G. Print Fig. 18

		<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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10	10	40	70	100	130	160	190		
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